



ICPLM452, ICPLM453

ELECTRICAL CHARACTERISTICS ($T_A = 0^\circ\text{C}$ to 70°C unless otherwise specified)

INPUT

Parameter	Symbol	Test Condition	Min	Typ.*	Max	Unit
Forward Voltage	V_F	$I_F = 16\text{mA}$		1.45	1.8	V
Reverse Voltage	V_R	$I_R = 10\mu\text{A}$, $T_A = 25^\circ\text{C}$	5.0			V
Temperature Coefficient of V_F	$\Delta V_F / \Delta T_A$	$I_F = 16\text{mA}$		-1.6		mV/ $^\circ\text{C}$

OUTPUT

Parameter	Symbol	Test Condition	Min	Typ.*	Max	Unit
High Level Supply Current	I_{CCH}	$I_F = 0\text{mA}$, $V_O = \text{Open}$, $V_{CC} = 15\text{V}$, $T_A = 25^\circ\text{C}$		0.05	1	μA
		$I_F = 0\text{mA}$, $V_O = \text{Open}$, $V_{CC} = 15\text{V}$			2	
Low Level Supply Current	I_{CCL}	$I_F = 16\text{mA}$, $V_O = \text{Open}$, $V_{CC} = 15\text{V}$		100	200	μA

COUPLED

Parameter	Symbol	Test Condition	Min	Typ.*	Max	Unit
Current Transfer Ratio	CTR	$I_F = 16\text{mA}$, $V_O = 0.4\text{V}$, $V_{CC} = 4.5\text{V}$, $T_A = 25^\circ\text{C}$	20		50	%
		$I_F = 16\text{mA}$, $V_O = 0.5\text{V}$, $V_{CC} = 4.5\text{V}$	15			
High Level Output Current	I_{OH}	$I_F = 0\text{mA}$, $V_O = V_{CC} = 5.5\text{V}$, $T_A = 25^\circ\text{C}$		0.001	0.5	μA
		$I_F = 0\text{mA}$, $V_O = V_{CC} = 15\text{V}$, $T_A = 25^\circ\text{C}$		0.001	1	
		$I_F = 0\text{mA}$, $V_O = V_{CC} = 15\text{V}$			50	
Low Level Output Voltage	V_{OL}	$I_F = 16\text{mA}$, $I_O = 3\text{mA}$, $V_{CC} = 4.5\text{V}$, $T_A = 25^\circ\text{C}$			0.4	V
		$I_F = 16\text{mA}$, $I_O = 2.4\text{mA}$, $V_{CC} = 4.5\text{V}$			0.5	

* Typical values at $T_A = 25^\circ\text{C}$



ICPLM452, ICPLM453

ELECTRICAL CHARACTERISTICS ($T_A = 0^\circ\text{C}$ to 70°C unless otherwise specified)

Switching Characteristics ($V_{CC} = 5\text{V}$ unless otherwise specified)

Parameter	Symbol	Test Condition	Min	Typ.*	Max	Unit
Propagation Delay Time to Logic Low	T_{PHL}	$I_F = 16\text{mA}$, $R_L = 1.9\text{k}\Omega$, $T_A = 25^\circ\text{C}$		0.4	0.8	μs
		$I_F = 16\text{mA}$, $R_L = 1.9\text{k}\Omega$,			1.0	
Propagation Delay Time to Logic High	T_{PLH}	$I_F = 16\text{mA}$, $R_L = 1.9\text{k}\Omega$, $T_A = 25^\circ\text{C}$		0.35	0.8	μs
		$I_F = 16\text{mA}$, $R_L = 1.9\text{k}\Omega$,			1.0	ns
Common Mode Transient Immunity at Logic High	CM_H	ICPLM452 $I_F = 0\text{mA}$, $R_L = 1.9\text{k}\Omega$, $V_{CM} = 10\text{Vp-p}$, $T_A = 25^\circ\text{C}$	5000			$\text{V}/\mu\text{s}$
		ICPLM453 $I_F = 0\text{mA}$, $R_L = 1.9\text{k}\Omega$, $V_{CM} = 1500\text{Vp-p}$, $T_A = 25^\circ\text{C}$	15000			
Common Mode Transient Immunity at Logic Low	CM_L	ICPLM452 $I_F = 16\text{mA}$, $R_L = 1.9\text{k}\Omega$, $V_{CM} = 10\text{Vp-p}$, $T_A = 25^\circ\text{C}$	5000			$\text{V}/\mu\text{s}$
		ICPLM453 $I_F = 16\text{mA}$, $R_L = 1.9\text{k}\Omega$, $V_{CM} = 1500\text{Vp-p}$, $T_A = 25^\circ\text{C}$	15000			

* Typical values at $T_A = 25^\circ\text{C}$

CM_H – The maximum tolerable rate of rise of the common mode voltage dV_{CM}/t , to ensure the output will remain in the HIGH state (i.e., $V_{OUT} > 2.0\text{V}$).

CM_L – The maximum tolerable rate of fall of the common mode voltage to dV_{CM}/t , to ensure the output will remain in the LOW output state (i.e., $V_{OUT} < 0.8\text{V}$).



ICPLM452, ICPLM453

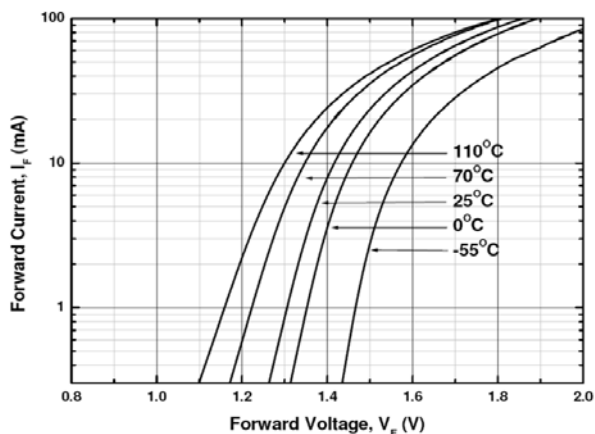


Fig 1 Forward Current vs Forward Voltage

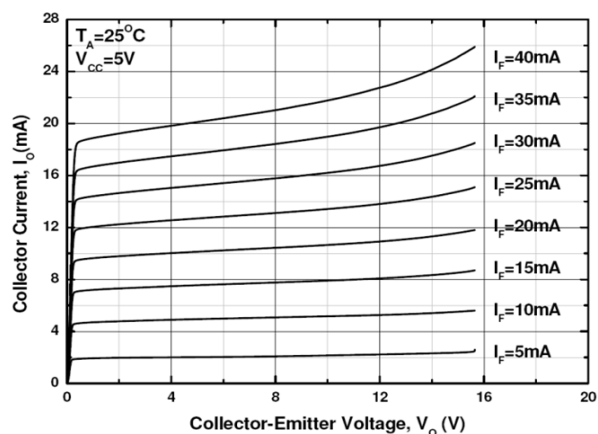


Fig 2 Output Current vs Output Voltage

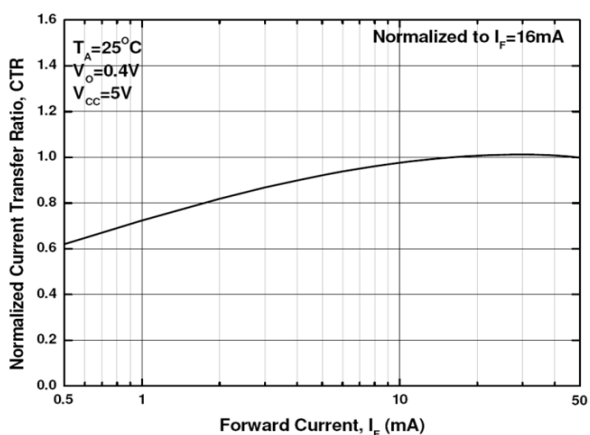


Fig 3 Normalized CTR vs Forward Current

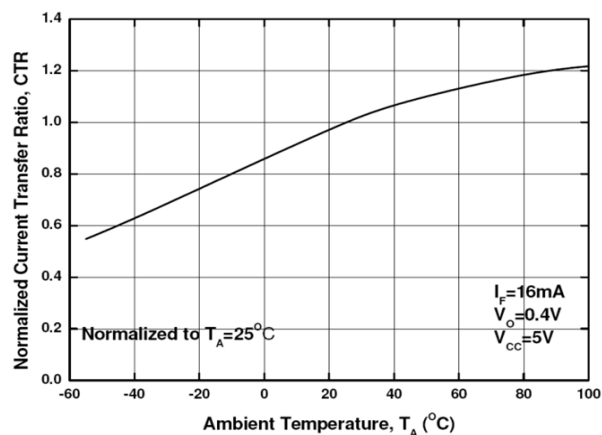


Fig 4 Normalized CTR vs T_A

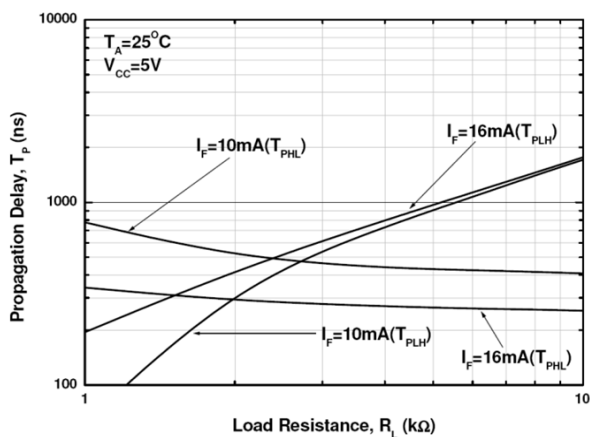


Fig 5 Propagation Delay vs Load Resistance

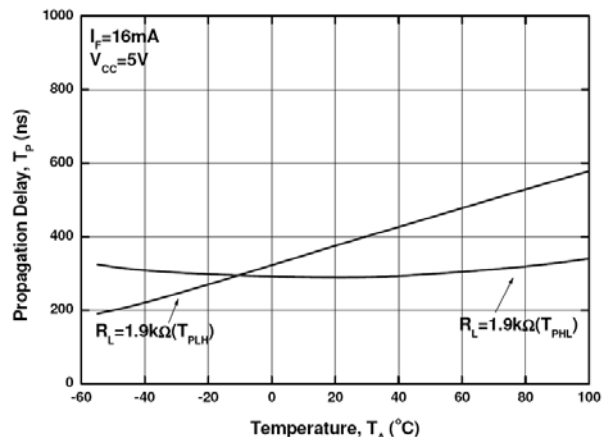


Fig 6 Propagation Delay vs T_A



ICPLM452, ICPLM453

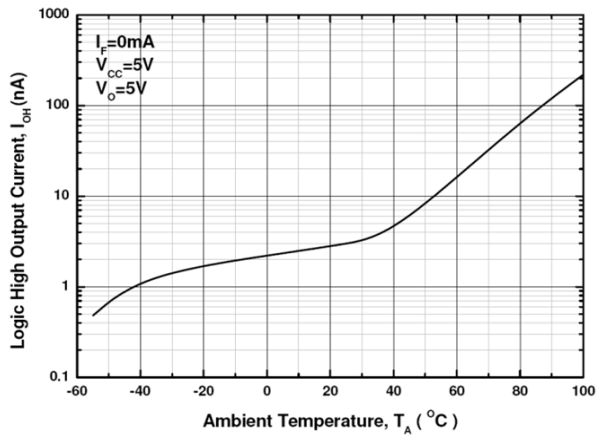


Fig 7 Logic High Output Current vs T_A

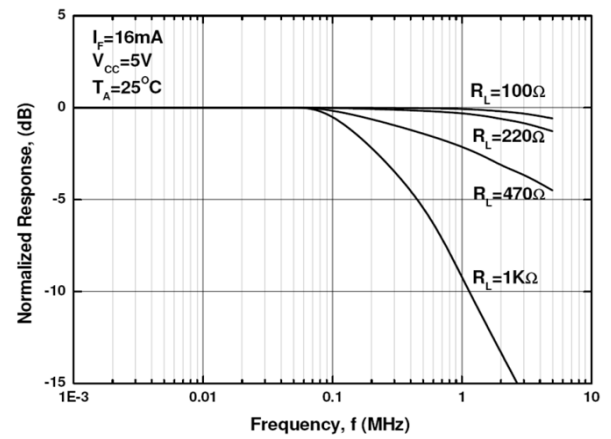


Fig 8 Frequency Response



ICPLM452, ICPLM453

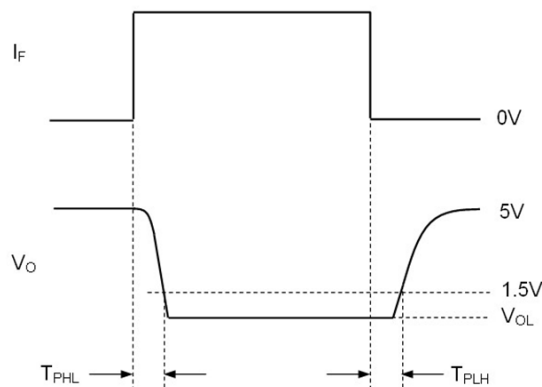
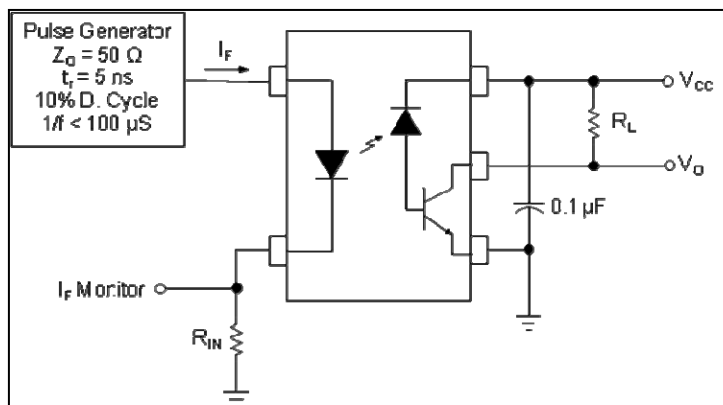


Fig 9 Switching Time Test Circuit

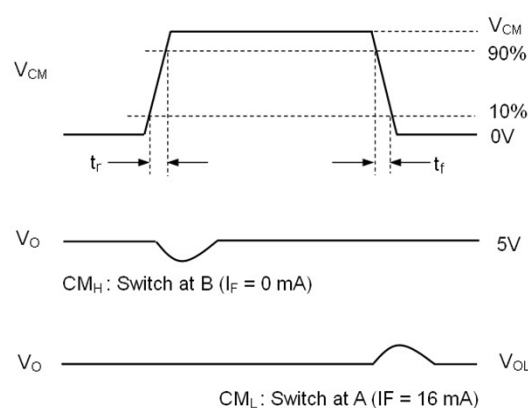
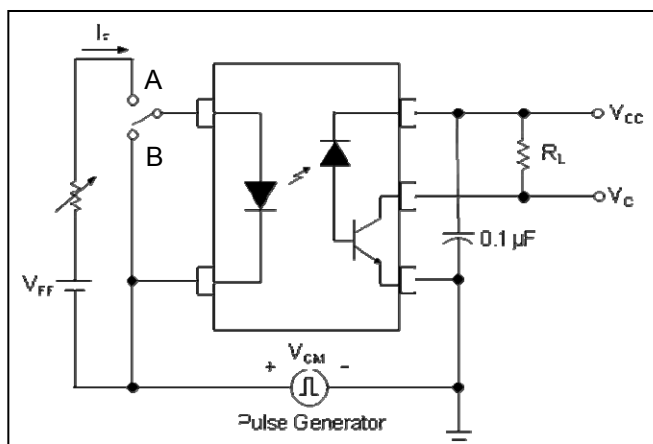


Fig 10 Common Mode Transient Immunity Test Circuit

Common mode transient immunity in logic high level is the maximum tolerable (positive) dV_{CM}/dt on the leading edge of the common mode pulse signal V_{CM} , to assure that the output will remain in a logic high state (i.e., $V_O > 2.0V$).

Common mode transient immunity in logic low level is the maximum tolerable (negative) dV_{CM}/dt on the trailing edge of the common mode pulse signal, V_{CM} , to assure that the output will remain in a logic low state (i.e., $V_O < 0.8V$).



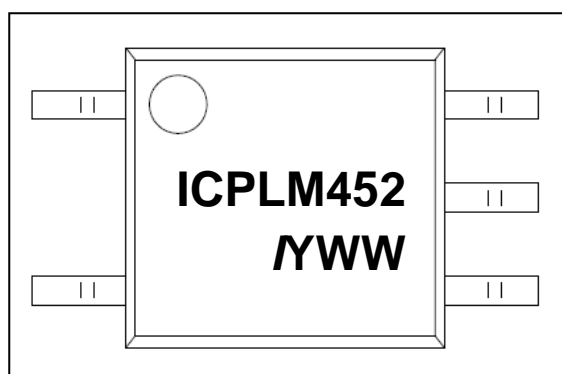
ISOCOM
COMPONENTS

ICPLM452, ICPLM453

ORDER INFORMATION

ICPLM452, ICPLM453			
After PN	PN	Description	Packing quantity
None	ICPLM452, ICPLM453	Surface Mount Tape & Reel	3000 pcs per reel

DEVICE MARKING

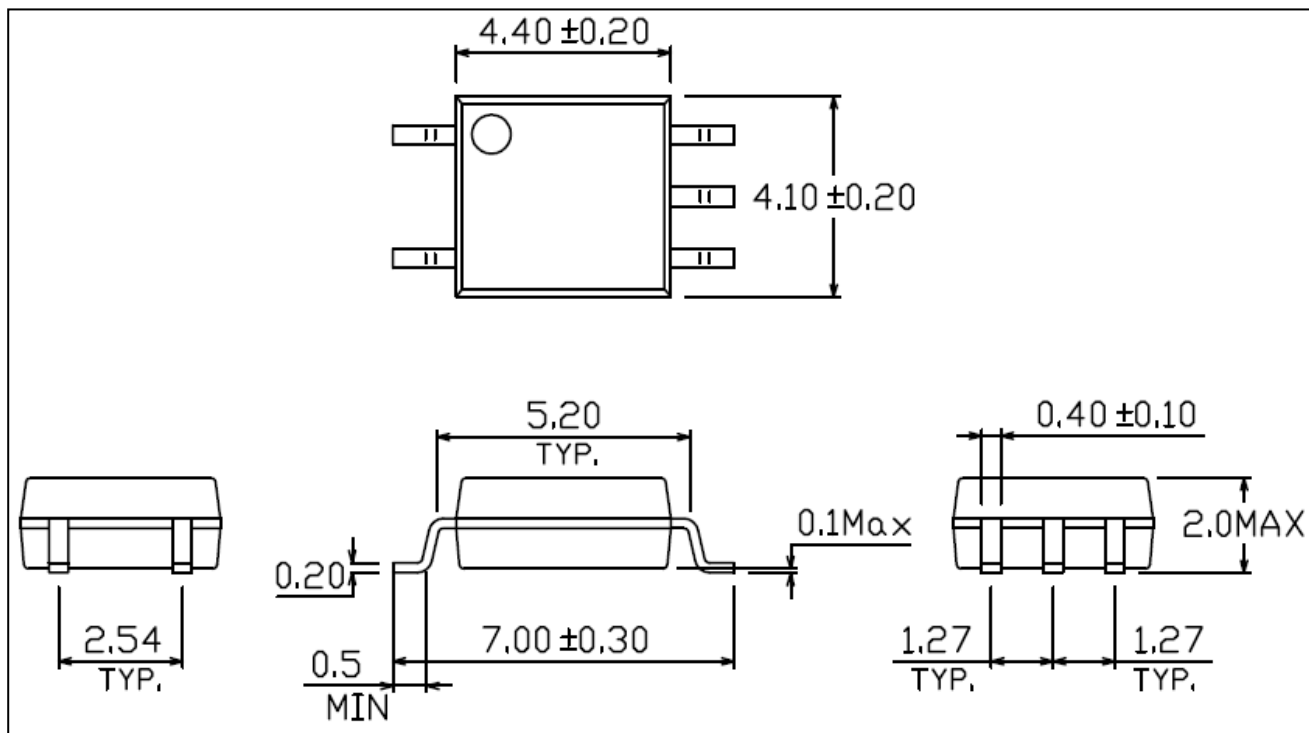


ICPLM600 denotes Device Part Number (ICPLM452 is used as example)
Y denotes 1 digit Year code
WW denotes 2 digit Week code
/ denotes Isocom

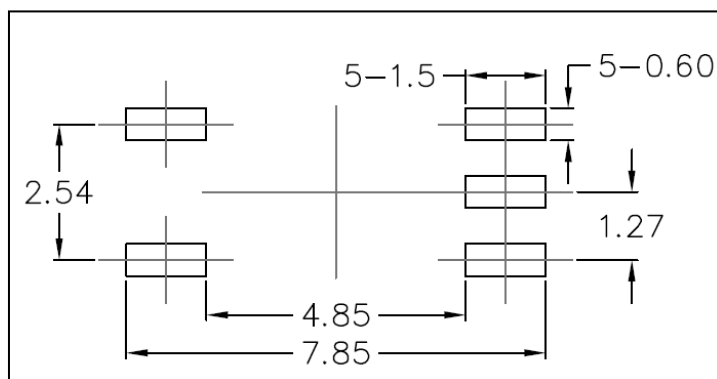


ICPLM452, ICPLM453

PACKAGE DIMENSIONS (mm)



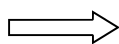
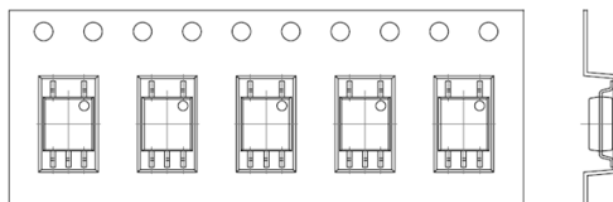
RECOMMENDED PAD LAYOUT (mm)



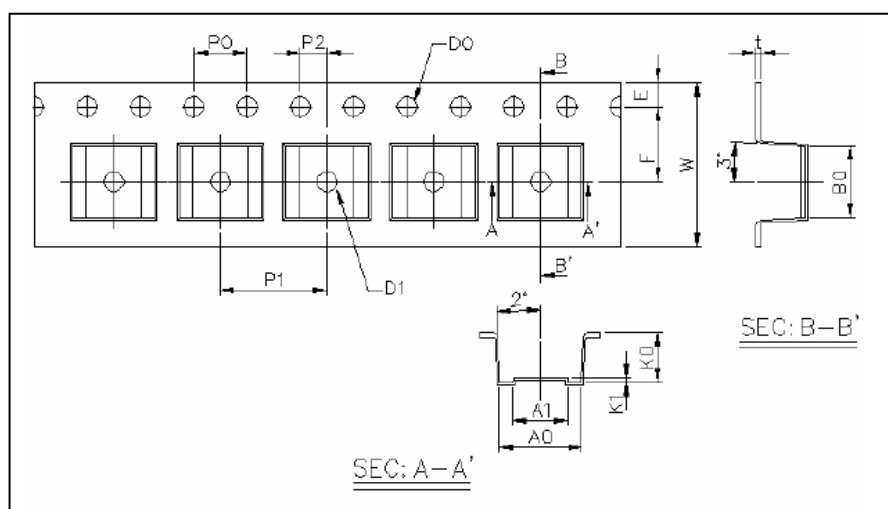


ICPLM452, ICPLM453

TAPE AND REEL PACKAGING



Direction of feed from reel

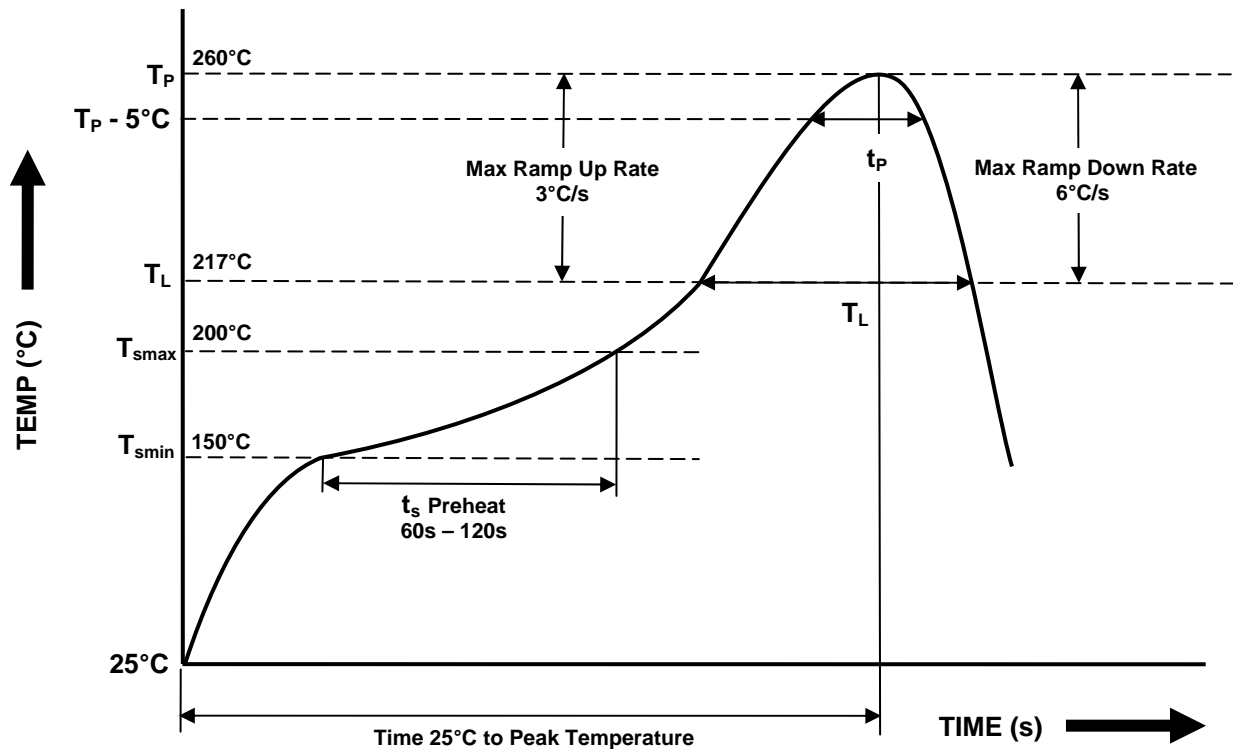


Dimension No.	A0	A1	B0	D0	D1	E	F
Dimension (mm)	6.2±0.1	4.1±0.1	5.28±0.1	1.5±0.1	1.5±0.3	1.75±0.1	5.5±0.1
Dimension No.	P0	P1	P2	t	W	K0	K0
Dimension (mm)	4.0±0.1	8.0±0.1	2.0±0.1	0.4±0.1	12.0 +0.3/-0.1	3.7±0.1	0.3±0.1



ICPLM452, ICPLM453

IR REFLOW SOLDERING TEMPERATURE PROFILE (One Time Reflow Soldering is Recommended)



Profile Details	Conditions
Preheat <ul style="list-style-type: none">- Min Temperature (T_{SMIN})- Max Temperature (T_{SMAX})- Time T_{SMIN} to T_{SMAX} (t_s)	150°C 200°C 60s - 120s
Soldering Zone <ul style="list-style-type: none">- Peak Temperature (T_P)- Liquidous Temperature (T_L)- Time within 5°C of Actual Peak Temperature ($T_P - 5^\circ\text{C}$)- Time maintained above T_L (t_L)- Ramp Up Rate (T_L to T_P)- Ramp Down Rate (T_P to T_L)	260°C 217°C 30s 60s - 100s 3°C/s max 6°C/s max
Average Ramp Up Rate (T_{smax} to T_P)	3°C/s max
Time 25°C to Peak Temperature	8 minutes max

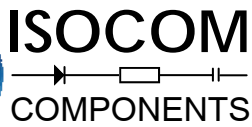


ISOCOM
— — — — —
COMPONENTS

ICPLM452, ICPLM453

NOTES :

- Isocom is continually improving the quality, reliability, function or design and Isocom reserves the right to make changes without further notices.
- The products shown in this publication are designed for the general use in electronic applications such as office automation equipment, communications devices, audio/visual equipment, electrical application and instrumentation.
- For equipment/application where high reliability or safety is required, such as space applications, nuclear power control equipment, medical equipment, etc., please contact our sales representatives.
- When requiring a device for any "specific" application, please contact our sales for advice.
- The contents described herein are subject to change without prior notice.
- Do not immerse device body in solder paste.



DISCLAIMER

ISOCOM is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing ISOCOM products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such ISOCOM products could cause loss of human life, bodily injury or damage to property.

In developing your designs, please ensure that ISOCOM products are used within specified operating ranges as set forth in the most recent ISOCOM products specifications.

___ The ISOCOM products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These ISOCOM products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury (“Unintended Usage”). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation Instruments, traffic signal instruments, combustion control instruments, medical Instruments, all types of safety devices, etc.. Unintended Usage of ISOCOM products listed in this document shall be made at the customer’s own risk.

___ Gallium arsenide (GaAs) is a substance used in the products described in this document. GaAs dust and fumes are toxic. Do not break, cut or pulverize the product, or use chemicals to dissolve them. When disposing of the products, follow the appropriate regulations. Do not dispose of the products with other industrial waste or with domestic garbage.

__ The products described in this document are subject to the foreign exchange and foreign trade laws.

___ The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by ISOCOM Components for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of ISOCOM Components or others.

The information contained herein is subject to change without notice.